

**Search Notes**

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Examiner

Alex Liew

Applicant(s)/Patent under  
Reexamination

FUKAGAWA ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/141-152 (limited to text search)	10/12/2006	AL